

SuperSharpSilicon™ - Non-Contact / Tapping Mode - High Resonance Frequency

NANOSENSORS™ SSS-NCH AFM probes are designed for non-contact mode or tapping mode AFM.

For enhanced resolution of nanostructures and microroughness we offer our SuperSharpSilicon™ AFM tip with unrivalled sharpness.

The AFM probe offers unique features:

- guaranteed AFM tip radius of curvature < 5 nm
- typical AFM tip radius of curvature of 2 nm
- typical aspect ratio at 200 nm from AFM tip apex in the order of 4:1
- half cone angle at 200 nm from apex < 10°
- monolithic material
- highly doped silicon to dissipate static charge
- chemically inert
- high mechanical Q-factor for high sensitivity

This AFM probe features alignment grooves on the back side of the holder chip. These grooves fit to the NANOSENSORS Alignment Chip.

Cantilever data:

Property	Nominal Value	Specified Range
Resonance Frequency [kHz]	330	204 - 497
Force Constant [N/m]	42	10 - 130
Length [µm]	125	115 - 135
Mean Width [µm]	30	30 - 45
Thickness [µm]	4	3 - 5

Order codes and shipping units:

Order Code	AFM probes per pack	Data sheet
SSS-NCH-10	10	of all probes
SSS-NCH-20	20	of all probes
SSS-NCH-50	50